

[54] PROCESS AND APPARATUS FOR X-RAY CRYSTALLOGRAPHY

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[57] ABSTRACT

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An X-ray crystallographic process, in which the intensity of the radiation ( $I_d$ ) diffracted by each constituent element, identified qualitatively by its angle of diffraction, and the intensity of the Compton radiation ( $I_c$ ) scattered by the whole sample, are measured, and the content  $C$  of each element is calculated by working out the ratio of the two measurements according to the formula  $I_d/I_c = K.C$ .

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[58] Field of Search ..... 250/273, 276, 277, 278, 250/272; 235/151.35

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9 Claims, 5 Drawing Figures

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